



Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Attorney Docket No. 0756-1936		Serial No. 09/255,777	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Applicant: Shunpei YAMAZAKI et al.			
				Filing Date: February 23, 1999		Group: 2812	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
11A	4,266,986	05/12/81	Benton et al	—	—		
11B	4,282,543	08/04/81	Ihara et al	—	—		
11C	4,461,071	07/24/84	Poleshuk	—	—		
11D	4,876,582	10/24/89	Janning	—	—		
11E	4,902,638	02/20/90	Muto	—	—		
11F	5,134,018	07/28/92	Tokunaga	—	—		
11G	5,147,826	09/15/92	Liu et al	—	—		
11H	5,275,851	01/04/94	Fonash et al	—	—		
11I	5,289,030	02/22/94	Yamazaki et al	—	—		
11J	5,374,570	12/20/94	Nasu et al	—	—		
11K	5,442,223	08/15/95	Fujii	—	—		
11L	5,485,019	01/16/96	Yamazaki et al	—	—		
11M	5,583,369	12/10/96	Yamazaki et al	—	—		
11N	5,736,751	04/07/98	Mano et al	—	—		
11O	5,946,561	08/31/99	Yamazaki et al	—	—		
Examiner <i>Robert A. K.</i>		Date Considered <i>2/5/01</i>					

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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		Filing Date: February 23, 1999				Group: 2812	
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	<u>Translation</u> <u>Yes</u> <u>No</u>	
DB	57-23429	05/18/82	Japan	—	—	Abstract	
DB	61-256663	11/14/86	Japan	—	—	Abstract	
DB	62-112128	05/23/87	Japan	—	—	Abstract	
DB	62-181419	08/08/87	Japan	—	—	Abstract	
DB	62-188373	08/17/87	Japan	—	—	Abstract	
DB	63-258063	10/25/88	Japan	—	—	Abstract	
DB	4-192466	07/10/92	Japan	—	—	Abstract	
DB	5-21763	01/29/93	Japan	—	—	Abstract	
DB	EP 0 474 289 A1	03/11/92	Europe	—	—	FULL	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
	Hempel et al., "Needle-Like Crystallization of Ni Doped Amorphous Silicon Thin Films", Solid State Communications, Vol. 85, No. 11, March 1993, pp. 921-924						
	Hayzelden et al., "In Situ Transmission Electron Microscopy Studies of Silicide-Mediated Crystallization of Amorphous Silicon", Applied Physics Letters, Vol. 60, No. 2, January 13, 1992, pp. 225-227						
	Dvurechenskii et al., "Transport Phenomena in Amorphous Silicon Doped by Ion Implantation of 3d Metals", Phys. Stat. Sol. (A), Vol. 95, (1986), pp. 635-640						
	Crowder et al., "DMOS FET with Common Field and Channel Doping", IBM Technical Disclosure Bulletin, Vol. 20, No. 4, September 1977, pp. 1617-1621						
	Fathimulla et al., "Reactively rf Magnetron Sputtered AlN Films as Gate Dielectric", J. Applied Physics, Vol. 54, No. 8, August 1983, pp. 4586-4589						
	Gerova et al., "Deposition of AlN Thin Films by Magnetron Reactive Sputtering", Thin Solid Films - Preparation and Characterization, Vol. 81, (1981, pp. 201-206						
DB	Liu et al., "Polycrystalline Silicon Thin Film Transistors on Corning 7059 Glass Substrates Using Short Time, Low-Temperature Processing", Applied Physics Letters, Vol. 62, No. 20, May 17, 1993, pp. 2554-2556						
Examiner	Richard H. [Signature]			Date Considered 2/5/01			
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Submitted February 23, 1999 (Resubmitted September 13, 2000)

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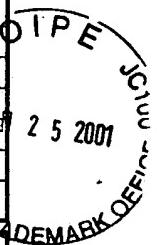
PTO/SB/08A (08-00)

Approved for use through 10/31/2002. OMB 0651-0031

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Substitute for form 1449A/PTO				Complete if Known	
				Application Number	09/255,777
				Filing Date	February 23, 1999
				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2812
				Examiner Name	R. Booth
Sheet	1	of	1	Attorney Docket Number	740756-1936



U.S. PATENT DOCUMENTS					
Examiner Initials ¹	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code ² (if known)		
RB		5,899,547		Yamazaki et al.	05/04/99
RB		RE 34,658		Yamazaki et al.	07/12/94
RB		4,581,620		Yamazaki et al.	04/08/86
RB		5,132,754		Serikawa et al.	07/21/92

FOREIGN PATENT DOCUMENTS					
Examiner Initials ¹	Cite No. ¹	Foreign Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Office ³	Number ⁴ Kind Code ⁵ (if known)		
RB		Japan	01-156725	Matsueda	06/20/89
RB		Japan	61-141174	Takeshita et al.	06/28/86
RB		Japan	53-027483	Shimada et al.	03/14/78
RB		Japan	62-216271	Yamazaki	09/22/87
RB		Japan	03-286520	Masatoshi et al.	12/17/91
RB		Japan	02-224253	Chiyuki Kou et al.	09/06/90
RB		Japan	02-228043	Takashi et al.	01/11/90
RB		Japan	02-224255	Seishiro et al.	09/06/90

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials ¹	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			

Examiner Signature	<i>Richard A. Booth</i>	Date Considered	2/5/01
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